Understanding Embedded - CPLDs (Complex Programmable Logic Devices)

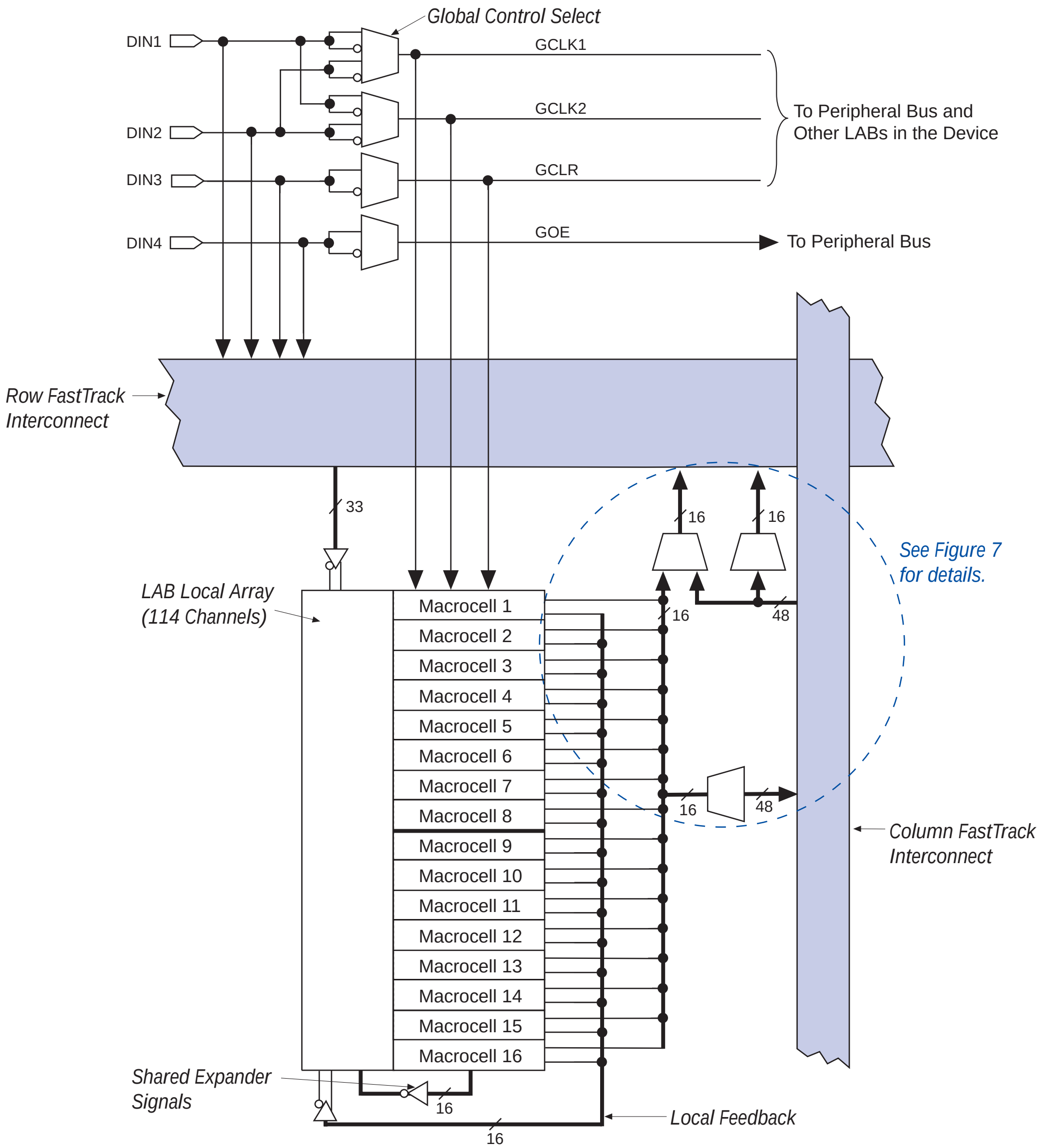
Embedded - CPLDs, or Complex Programmable Logic Devices, are highly versatile digital logic devices used in electronic systems. These programmable components are designed to perform complex logical operations and can be customized for specific applications. Unlike fixed-function ICs, CPLDs offer the flexibility to reprogram their configuration, making them an ideal choice for various embedded systems. They consist of a set of logic gates and programmable interconnects, allowing designers to implement complex logic circuits without needing custom hardware.

Applications of Embedded - CPLDs

Details	
Product Status	Obsolete
Programmable Type	In System Programmable
Delay Time tpd(1) Max	15 ns
Voltage Supply - Internal	4.75V ~ 5.25V
Number of Logic Elements/Blocks	20
Number of Macrocells	320
Number of Gates	6000
Number of I/O	132
Operating Temperature	0°C ~ 70°C (TA)
Mounting Type	Surface Mount
Package / Case	208-BFQFP Exposed Pad
Supplier Device Package	208-RQFP (28x28)
Purchase URL	https://www.e-xfl.com/product-detail/intel/epm9320rc208-15

LABs drive the row and column interconnect directly. Each macrocell can drive out of the LAB onto one or both routing resources. Once on the row or column interconnect, signals can traverse to other LABs or to the IOCs.

Figure 2. MAX 9000 Logic Array Block



Expander Product Terms

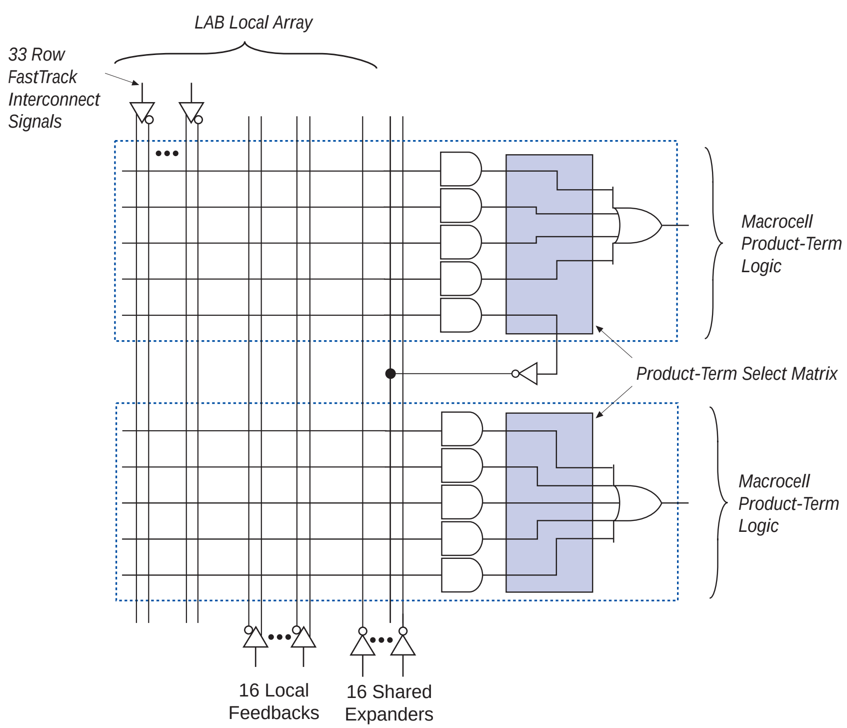
Although most logic functions can be implemented with the five product terms available in each macrocell, some logic functions are more complex and require additional product terms. Although another macrocell can supply the required logic resources, the MAX 9000 architecture also offers both shareable and parallel expander product terms that provide additional product terms directly to any macrocell in the same LAB. These expanders help ensure that logic is synthesized with the fewest possible logic resources to obtain the fastest possible speed.

Shareable Expanders

Each LAB has 16 shareable expanders that can be viewed as a pool of uncommitted single product terms (one from each macrocell) with inverted outputs that feed back into the LAB local array. Each shareable expander can be used and shared by any or all macrocells in the LAB to build complex logic functions. A small delay ($t_{LOCAL} + t_{SEXP}$) is incurred when shareable expanders are used. Figure 4 shows how shareable expanders can feed multiple macrocells.

Figure 4. MAX 9000 Shareable Expanders

Shareable expanders can be shared by any or all macrocells in the LAB.

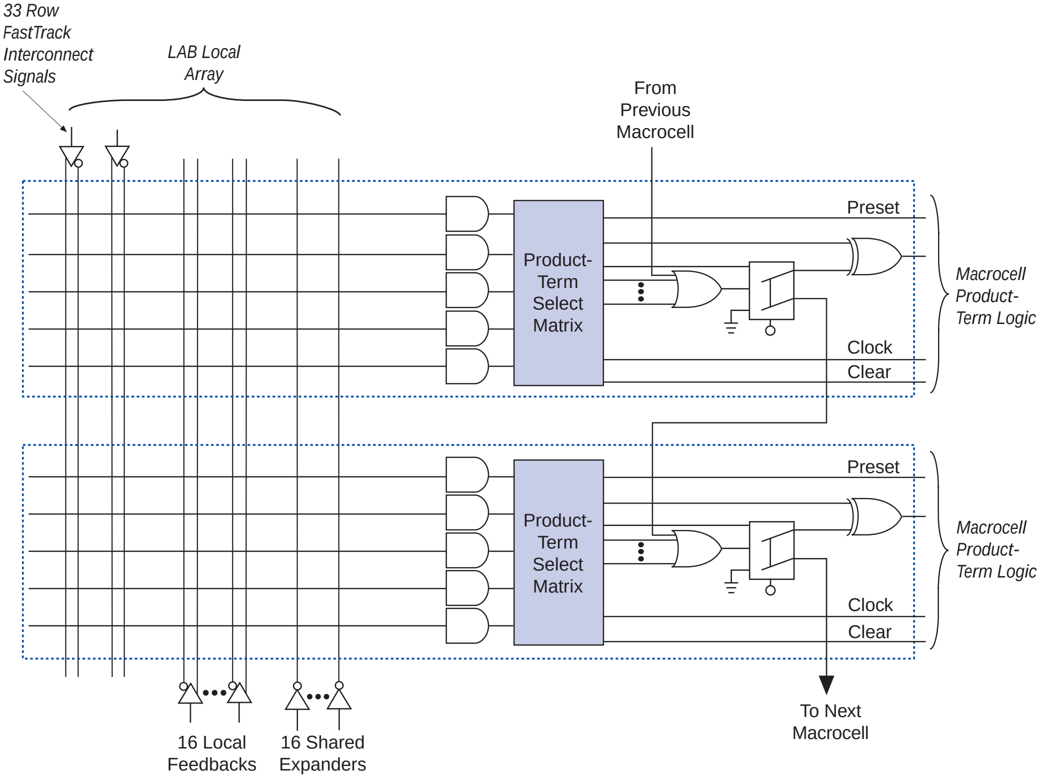


Parallel Expanders

Parallel expanders are unused product terms that can be allocated to a neighboring macrocell to implement fast, complex logic functions. Parallel expanders allow up to 20 product terms to directly feed the macrocell OR logic, with five product terms provided by the macrocell and 15 parallel expanders provided by neighboring macrocells in the LAB. Figure 5 shows how parallel expanders can feed the neighboring macrocell.

Figure 5. MAX 9000 Parallel Expanders

Unused product terms in a macrocell can be allocated to a neighboring macrocell.



The MAX+PLUS II Compiler automatically allocates as many as three sets of up to five parallel expanders to macrocells that require additional product terms. Each set of expanders incurs a small, incremental timing delay (t_{PEXP}). For example, if a macrocell requires 14 product terms, the Compiler uses the five dedicated product terms within the macrocell and allocates two sets of parallel expanders; the first set includes five product terms and the second set includes four product terms, increasing the total delay by $2 \times t_{PEXP}$.

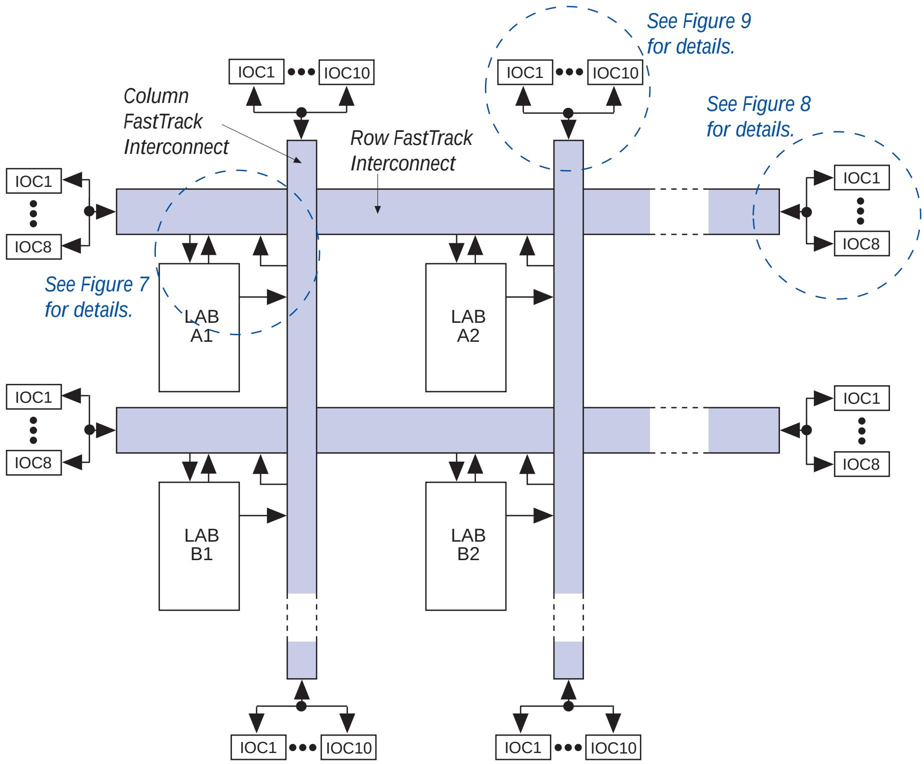
Two groups of eight macrocells within each LAB (e.g., macrocells 1 through 8 and 9 through 16) form two chains to lend or borrow parallel expanders. A macrocell borrows parallel expanders from lower-numbered macrocells. For example, macrocell 8 can borrow parallel expanders from macrocell 7, from macrocells 7 and 6, or from macrocells 7, 6, and 5. Within each group of 8, the lowest-numbered macrocell can only lend parallel expanders and the highest-numbered macrocell can only borrow them.

FastTrack Interconnect

In the MAX 9000 architecture, connections between macrocells and device I/O pins are provided by the FastTrack Interconnect, a series of continuous horizontal and vertical routing channels that traverse the entire device. This device-wide routing structure provides predictable performance even in complex designs. In contrast, the segmented routing in FPGAs requires switch matrices to connect a variable number of routing paths, increasing the delays between logic resources and reducing performance. Figure 6 shows the interconnection of four adjacent LABs with row and column interconnects.

Figure 6. MAX 9000 Device Interconnect Resources

Each LAB is named on the basis of its physical row (A, B, C, etc.) and column (1, 2, 3, etc.) position within the device.

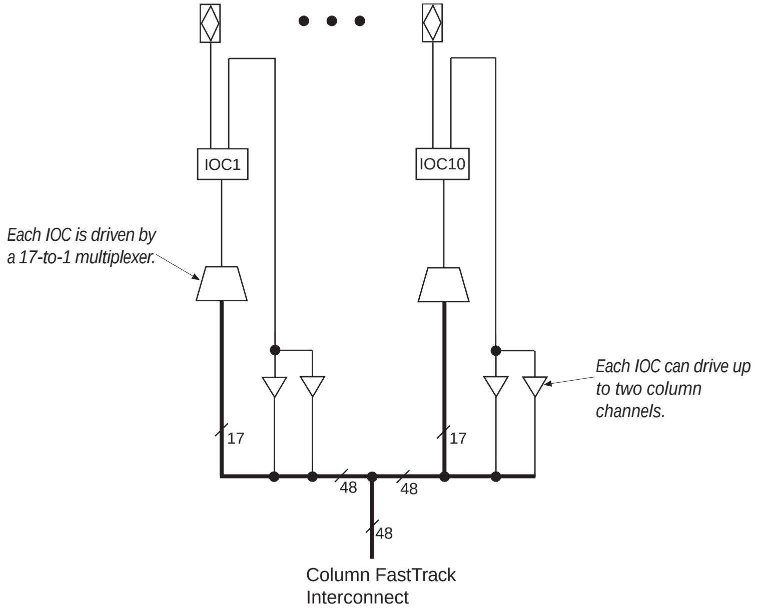


The LABs within MAX 9000 devices are arranged into a matrix of columns and rows. Table 5 shows the number of columns and rows in each MAX 9000 device.

Table 5. MAX 9000 Rows & Columns

Devices	Rows	Columns
EPM9320, EPM9320A	4	5
EPM9400	5	5
EPM9480	6	5
EPM9560, EPM9560A	7	5

Figure 9. MAX 9000 Column-to-IOC Connections



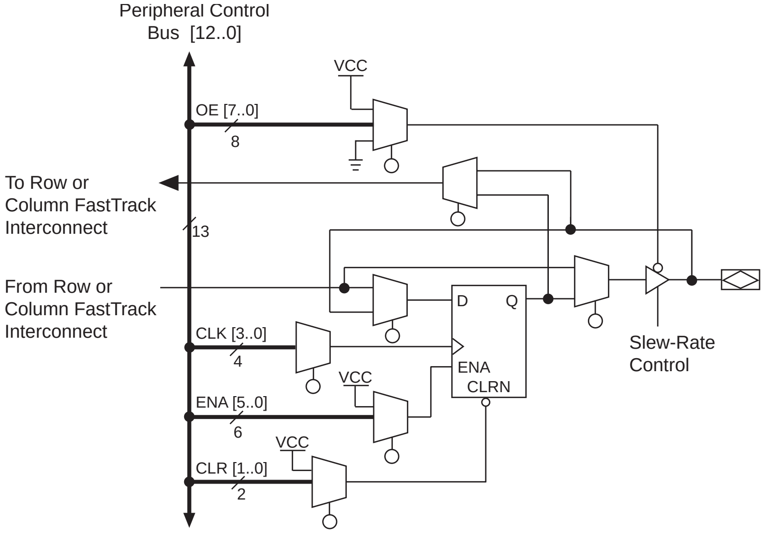
Dedicated Inputs

In addition to the general-purpose I/O pins, MAX 9000 devices have four dedicated input pins. These dedicated inputs provide low-skew, device-wide signal distribution to the LABs and IOCs in the device, and are typically used for global clock, clear, and output enable control signals. The global control signals can feed the macrocell or IOC clock and clear inputs, as well as the IOC output enable. The dedicated inputs can also be used as general-purpose data inputs because they can feed the row FastTrack Interconnect (see Figure 2 on page 7).

I/O Cells

Figure 10 shows the IOC block diagram. Signals enter the MAX 9000 device from either the I/O pins that provide general-purpose input capability or from the four dedicated inputs. The IOCs are located at the ends of the row and column interconnect channels.

Figure 10. MAX 9000 IOC



I/O pins can be used as input, output, or bidirectional pins. Each IOC has an IOC register with a clock enable input. This register can be used either as an input register for external data that requires fast setup times, or as an output register for data that requires fast clock-to-output performance. The IOC register clock enable allows the global clock to be used for fast clock-to-output performance, while maintaining the flexibility required for selective clocking.

The clock, clock enable, clear, and output enable controls for the IOCs are provided by a network of I/O control signals. These signals can be supplied by either the dedicated input pins or internal logic. The IOC control-signal paths are designed to minimize the skew across the device. All control-signal sources are buffered onto high-speed drivers that drive the signals around the periphery of the device. This “peripheral bus” can be configured to provide up to eight output enable signals, up to four clock signals, up to six clock enable signals, and up to two clear signals. Table 6 on page 18 shows the sources that drive the peripheral bus and how the IOC control signals share the peripheral bus.

The VCCIO pins can be connected to either a 3.3-V or 5.0-V power supply, depending on the output requirements. When the VCCIO pins are connected to a 5.0-V power supply, the output levels are compatible with 5.0-V systems. When the VCCIO pins are connected to a 3.3-V power supply, the output high is at 3.3 V and is therefore compatible with 3.3-V or 5.0-V systems. Devices operating with V_{CCIO} levels lower than 4.75 V incur a nominally greater timing delay of t_{OD2} instead of t_{OD1}.

In-System Programmability (ISP)

MAX 9000 devices can be programmed in-system through a 4-pin JTAG interface. ISP offers quick and efficient iterations during design development and debug cycles. The MAX 9000 architecture internally generates the 12.0-V programming voltage required to program EEPROM cells, eliminating the need for an external 12.0-V power supply to program the devices on the board. During ISP, the I/O pins are tri-stated to eliminate board conflicts.

ISP simplifies the manufacturing flow by allowing the devices to be mounted on a printed circuit board with standard pick-and-place equipment before they are programmed. MAX 9000 devices can be programmed by downloading the information via in-circuit testers, embedded processors, or the Altera BitBlaster, ByteBlaster, or ByteBlasterMV download cable. (The ByteBlaster cable is obsolete and has been replaced by the ByteBlasterMV cable, which can interface with 2.5-V, 3.3-V, and 5.0-V devices.) Programming the devices after they are placed on the board eliminates lead damage on high pin-count packages (e.g., QFP packages) due to device handling. MAX 9000 devices can also be reprogrammed in the field (i.e., product upgrades can be performed in the field via software or modem).

In-system programming can be accomplished with either an adaptive or constant algorithm. An adaptive algorithm reads information from the unit and adapts subsequent programming steps to achieve the fastest possible programming time for that unit. Because some in-circuit testers platforms have difficulties supporting an adaptive algorithm, Altera offers devices tested with a constant algorithm. Devices tested to the constant algorithm have an “F” suffix in the ordering code.

Programming with External Hardware

MAX 9000 devices can be programmed on Windows-based PCs with an Altera Logic Programmer card, the Master Programming Unit (MPU), and the appropriate device adapter. The MPU performs continuity checking to ensure adequate electrical contact between the adapter and the device.

For more information, see the *Altera Programming Hardware Data Sheet*.

The MAX+PLUS II software can use text- or waveform-format test vectors created with the MAX+PLUS II Text Editor or Waveform Editor to test a programmed device. For added design verification, designers can perform functional testing to compare the functional behavior of a MAX 9000 device with the results of simulation.

Data I/O, BP Microsystems, and other programming hardware manufacturers also provide programming support for Altera devices.

For more information, see *Programming Hardware Manufacturers.*

IEEE Std. 1149.1 (JTAG) Boundary-Scan Support

MAX 9000 devices support JTAG BST circuitry as specified by IEEE Std. 1149.1-1990. Table 10 describes the JTAG instructions supported by the MAX 9000 family. The pin-out tables starting on page 38 show the location of the JTAG control pins for each device. If the JTAG interface is not required, the JTAG pins are available as user I/O pins.

Table 10. MAX 9000 JTAG Instructions

JTAG Instruction	Description
SAMPLE/PRELOAD	Allows a snapshot of signals at the device pins to be captured and examined during normal device operation, and permits an initial data pattern output at the device pins.
EXTEST	Allows the external circuitry and board-level interconnections to be tested by forcing a test pattern at the output pins and capturing test results at the input pins.
BYPASS	Places the 1-bit bypass register between the `TDI` and `TDO` pins, which allows the BST data to pass synchronously through a selected device to adjacent devices during normal device operation.
IDCODE	Selects the IDCODE register and places it between `TDI` and `TDO`, allowing the IDCODE to be shifted out of `TDO`. Supported by the EPM9320A, EPM9400, EPM9480, and EPM9560A devices only.
UESCODE	Selects the user electronic signature (UESCODE) register and allows the UESCODE to be shifted out of `TDO` serially. This instruction is supported by MAX 9000A devices only.
ISP Instructions	These instructions are used when programming MAX 9000 devices via the JTAG ports with the BitBlaster or ByteBlasterMV download cable, or using a Jam File (**.jam**), Jam Byte-Code File (**.jbc**), or Serial Vector Format (**.svf**) File via an embedded processor or test equipment.

The instruction register length for MAX 9000 devices is 10 bits. EPM9320A and EPM9560A devices support a 16-bit UESCODE register. Tables 11 and 12 show the boundary-scan register length and device IDCODE information for MAX 9000 devices.

Table 11. MAX 9000 Boundary-Scan Register Length	
Device	**Boundary-Scan Register Length**
EPM9320, EPM9320A	504
EPM9400	552
EPM9480	600
EPM9560, EPM9560A	648

Table 12. 32-Bit MAX 9000 Device IDCODE *Note (1)*

Device	**IDCODE (32 Bits)**			
	Version (4 Bits)	**Part Number (16 Bits)** *(2)*	**Manufacturer's Identity (11 Bits)**	**1 (1 Bit)**
EPM9320A *(3)*	0000	1001 0011 0010 0000	00001101110	1
EPM9400	0000	1001 0100 0000 0000	00001101110	1
EPM9480	0000	1001 0100 1000 0000	00001101110	1
EPM9560A *(3)*	0000	1001 0101 0110 0000	00001101110	1

Notes:

(1) The IDCODE's least significant bit (LSB) is always 1.

(2) The most significant bit (MSB) is on the left.

(3) Although the EPM9320A and EPM9560A devices support the IDCODE instruction, the EPM9320 and EPM9560 devices do not.

Figure 11 shows the timing requirements for the JTAG signals.

Programmable Speed/Power Control

MAX 9000 devices offer a power-saving mode that supports low-power operation across user-defined signal paths or the entire device. Because most logic applications require only a small fraction of all gates to operate at maximum frequency, this feature allows total power dissipation to be reduced by 50% or more.

The designer can program each individual macrocell in a MAX 9000 device for either high-speed (i.e., with the Turbo Bit™ option turned on) or low-power (i.e., with the Turbo Bit option turned off) operation. As a result, speed-critical paths in the design can run at high speed, while remaining paths operate at reduced power. Macrocells that run at low power incur a nominal timing delay adder (t_{LPA}) for the LAB local array delay (t_{LOCAL}).

Design Security

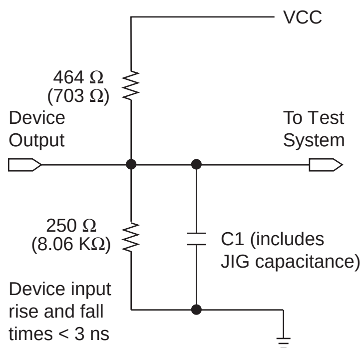
All MAX 9000 EPLDs contain a programmable security bit that controls access to the data programmed into the device. When this bit is programmed, a proprietary design implemented in the device cannot be copied or retrieved. This feature provides a high level of design security, because programmed data within EEPROM cells is invisible. The security bit that controls this function, as well as all other programmed data, is reset only when the device is erased.

Generic Testing

MAX 9000 EPLDs are fully functionally tested. Complete testing of each programmable EEPROM bit and all logic functionality ensures 100% programming yield. AC test measurements are taken under conditions equivalent to those shown in Figure 12. Test patterns can be used and then erased during the early stages of the production flow.

Figure 12. MAX 9000 AC Test Conditions

Power supply transients can affect AC measurements. Simultaneous transitions of multiple outputs should be avoided for accurate measurement. Threshold tests must not be performed under AC conditions. Large-amplitude, fast ground-current transients normally occur as the device outputs discharge the load capacitances. When these transients flow through the parasitic inductance between the device ground pin and the test system ground, significant reductions in observable noise immunity can result. Numbers in parentheses are for 3.3-V outputs. Numbers without parentheses are for 5.0-V devices or outputs.



Operating Conditions

Tables 14 through 20 provide information on absolute maximum ratings, recommended operating conditions, operating conditions, and capacitance for MAX 9000 devices.

Table 14. MAX 9000 Device Absolute Maximum Ratings *Note (1)*

Symbol	Parameter	Conditions	Min	Max	Unit
V_{CC}	Supply voltage	With respect to ground *(2)*	–2.0	7.0	V
V_I	DC input voltage		–2.0	7.0	V
V_{CCISP}	Supply voltage during in-system programming		–2.0	7.0	V
I_{OUT}	DC output current, per pin		–25	25	mA
T_{STG}	Storage temperature	No bias	–65	150	° C
T_{AMB}	Ambient temperature	Under bias	–65	135	° C
T_J	Junction temperature	Ceramic packages, under bias		150	° C
		PQFP and RQFP packages, under bias		135	° C

Table 15. MAX 9000 Device Recommended Operating Conditions

Symbol	Parameter	Conditions	Min	Max	Unit
V_{CCINT}	Supply voltage for internal logic and input buffers	*(3)*, *(4)*	4.75 (4.50)	5.25 (5.50)	V
V_{CCIO}	Supply voltage for output drivers, 5.0-V operation	*(3)*, *(4)*	4.75 (4.50)	5.25 (5.50)	V
	Supply voltage for output drivers, 3.3-V operation	*(3)*, *(4)*	3.00 (3.00)	3.60 (3.60)	V
V_{CCISP}	Supply voltage during in-system programming		4.75	5.25	V
V_I	Input voltage		–0.5	V_{CCINT} + 0.5	V
V_O	Output voltage		0	V_{CCIO}	V
T_A	Ambient temperature	For commercial use	0	70	° C
		For industrial use	–40	85	° C
T_J	Junction temperature	For commercial use	0	90	° C
		For industrial use	–40	105	° C
t_R	Input rise time			40	ns
t_F	Input fall time			40	ns

Table 20. MAX 9000A Device Typical I_{CC} Supply Current Values

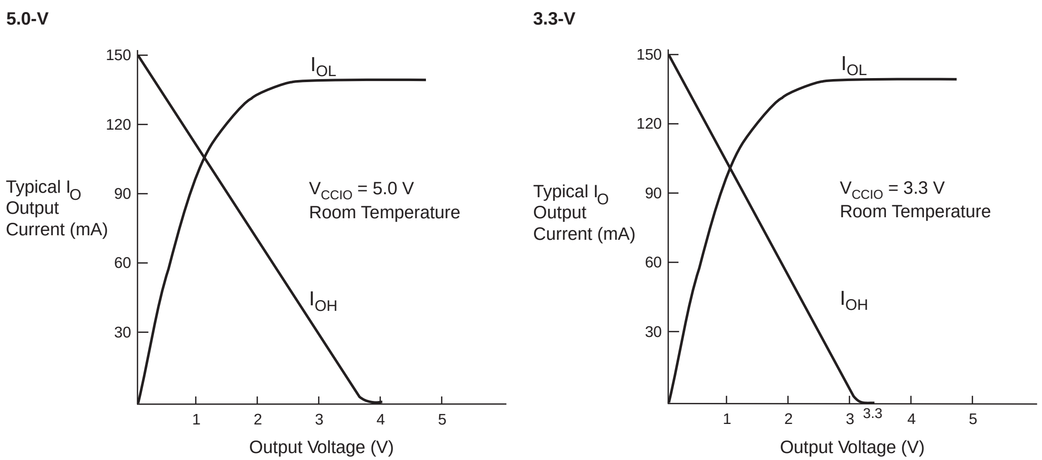
Symbol	Parameter	Conditions	EPM9320A	EPM9560A	Unit
I_{CC1}	I_{CC} supply current (low-power mode, standby, typical)	V_I = ground, no load *(11)*	99	174	mA

Notes to tables:

(1) See the *Operating Requirements for Altera Devices Data Sheet*.
(2) Minimum DC input on I/O pins is –0.5 V and on the four dedicated input pins is –0.3 V. During transitions, the inputs may undershoot to –2.0 V or overshoot to 7.0 V for periods shorter than 20 ns under no-load conditions.
(3) V_{CC} must rise monotonically.
(4) Numbers in parentheses are for industrial-temperature-range devices.
(5) Typical values are for T_A = 25° C and V_{CC} = 5.0 V.
(6) These values are specified under the MAX 9000 recommended operating conditions, shown in Table 15 on page 27.
(7) During in-system programming, the minimum V_{IH} of the JTAG `TCK` pin is 3.6 V. The minimum V_{IH} of this pin during JTAG testing remains at 2.0 V. To attain this 3.6-V V_{IH} during programming, the ByteBlaster and ByteBlasterMV download cables must have a 5.0-V V_{CC}.
(8) This parameter is measured with 50% of the outputs each sinking 12 mA. The I_{OH} parameter refers to high-level TTL or CMOS output current; the I_{OL} parameter refers to the low-level TTL or CMOS output current.
(9) JTAG pin input leakage is typically –60 µA.
(10) Capacitance is sample-tested only and is measured at 25° C.
(11) Measured with a 16-bit loadable, enabled, up/down counter programmed into each LAB. I_{CC} is measured at 0° C.

Figure 13 shows typical output drive characteristics for MAX 9000 devices with 5.0-V and 3.3-V V_{CCIO}.

Figure 13. Output Drive Characteristics of MAX 9000 Devices *Note (1)*



Note:

(1) Output drive characteristics include the JTAG `TDO` pin.

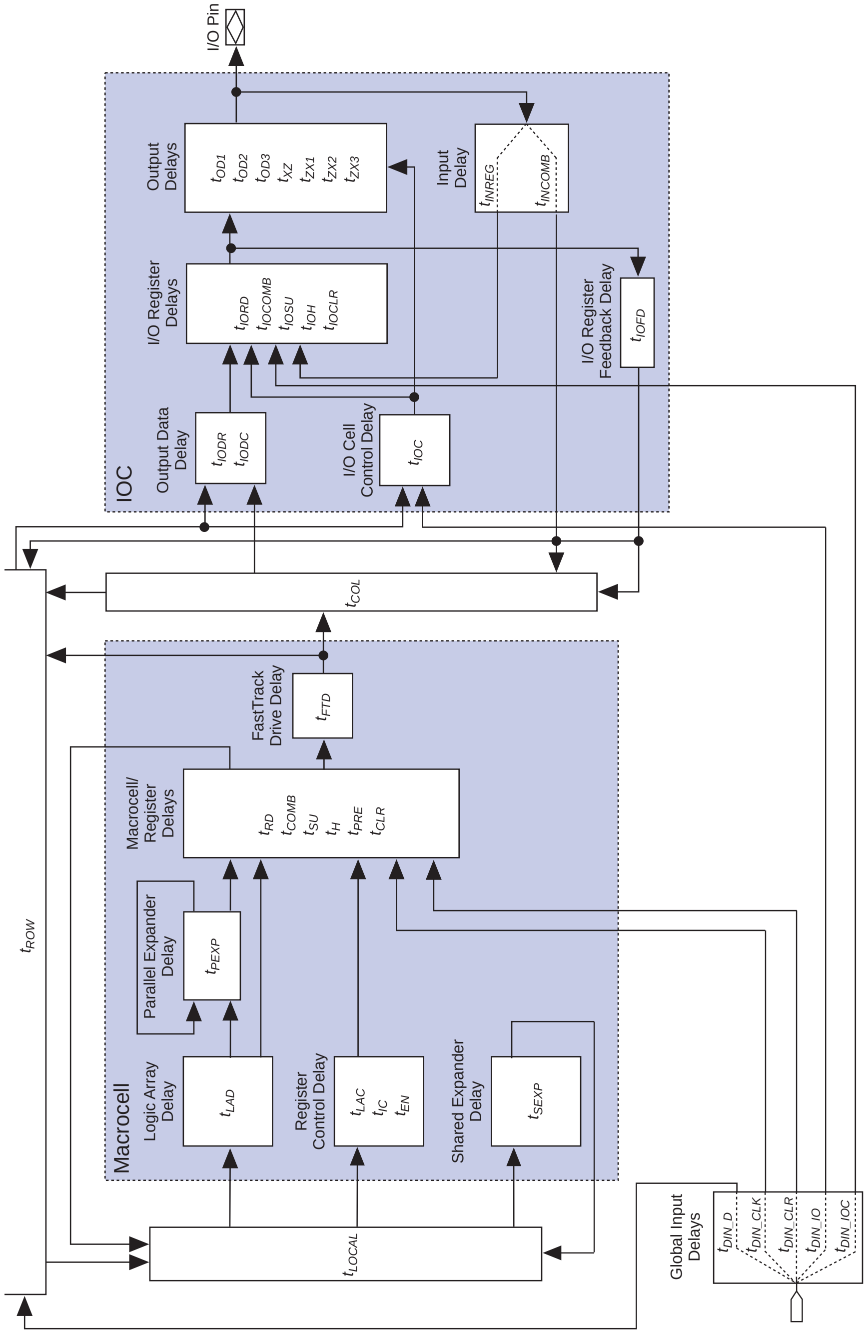
Timing Model

The continuous, high-performance FastTrack Interconnect ensures predictable performance and accurate simulation and timing analysis. This predictable performance contrasts with that of FPGAs, which use a segmented connection scheme and hence have unpredictable performance. Timing simulation and delay prediction are available with the MAX+PLUS II Simulator and Timing Analyzer, or with industry-standard EDA tools. The Simulator offers both pre-synthesis functional simulation to evaluate logic design accuracy and post-synthesis timing simulation with 0.1-ns resolution. The Timing Analyzer provides point-to-point timing delay information, setup and hold time prediction, and device-wide performance analysis.

The MAX 9000 timing model in Figure 14 shows the delays that correspond to various paths and functions in the circuit. This model contains three distinct parts: the macrocell, IOC, and interconnect, including the row and column FastTrack Interconnect and LAB local array paths. Each parameter shown in Figure 14 is expressed as a worst-case value in the internal timing characteristics tables in this data sheet. Hand-calculations that use the MAX 9000 timing model and these timing parameters can be used to estimate MAX 9000 device performance.

For more information on calculating MAX 9000 timing delays, see *Application Note 77 (Understanding MAX 9000 Timing)*.

Figure 14. MAX 9000 Timing Model



Tables 21 through 24 show timing for MAX 9000 devices.

Table 21. MAX 9000 External Timing Characteristics *Note (1)*

Symbol	Parameter	Conditions		Speed Grade						Unit
				-10		-15		-20		
				Min	Max	Min	Max	Min	Max	
t_{PD1}	Row I/O pin input to row I/O pin output	C1 = 35 pF *(2)*			10.0		15.0		20.0	ns
t_{PD2}	Column I/O pin input to column I/O pin output	C1 = 35 pF *(2)*	EPM9320A		10.8					ns
			EPM9320				16.0		23.0	ns
			EPM9400				16.2		23.2	ns
			EPM9480				16.4		23.4	ns
			EPM9560A		11.4					ns
			EPM9560				16.6		23.6	ns
t_{FSU}	Global clock setup time for I/O cell			3.0		5.0		6.0		ns
t_{FH}	Global clock hold time for I/O cell			0.0		0.0		0.0		ns
t_{FCO}	Global clock to I/O cell output delay	C1 = 35 pF		1.0 *(3)*	4.8	1.0 *(3)*	7.0	1.0 *(3)*	8.5	ns
t_{CNT}	Minimum internal global clock period	*(4)*			6.9		8.5		10.0	ns
f_{CNT}	Maximum internal global clock frequency	*(4)*		144.9		117.6		100.0		MHz

Table 24. Interconnect Delays

Symbol	Parameter	Conditions	Speed Grade						Unit
			-10		-15		-20		
			Min	Max	Min	Max	Min	Max	
t_{LOCAL}	LAB local array delay			0.5		0.5		0.5	ns
t_{ROW}	FastTrack row delay	*(6)*		0.9		1.4		2.0	ns
t_{COL}	FastTrack column delay	*(6)*		0.9		1.7		3.0	ns
t_{DIN_D}	Dedicated input data delay			4.0		4.5		5.0	ns
t_{DIN_CLK}	Dedicated input clock delay			2.7		3.5		4.0	ns
t_{DIN_CLR}	Dedicated input clear delay			4.5		5.0		5.5	ns
t_{DIN_IOC}	Dedicated input I/O register clock delay			2.5		3.5		4.5	ns
t_{DIN_IO}	Dedicated input I/O register control delay			5.5		6.0		6.5	ns

Notes to tables:

(1) These values are specified under the MAX 9000 device recommended operating conditions, shown in Table 15 on page 27.
(2) See *Application Note 77 (Understanding MAX 9000 Timing)* for more information on test conditions for $\mathbf{t_{PD1}}$ and $\mathbf{t_{PD2}}$ delays.
(3) This parameter is a guideline that is sample-tested only. It is based on extensive device characterization. This parameter applies for both global and array clocking as well as both macrocell and I/O cell registers.
(4) Measured with a 16-bit loadable, enabled, up/down counter programmed in each LAB.
(5) The t_{LPA} parameter must be added to the t_{LOCAL} parameter for macrocells running in low-power mode.
(6) The t_{ROW}, t_{COL}, and t_{IOC} delays are worst-case values for typical applications. Post-compilation timing simulation or timing analysis is required to determine actual worst-case performance.

Power Consumption

The supply power (P) versus frequency ($\mathbf{f_{MAX}}$) for MAX 9000 devices can be calculated with the following equation:

$$P = P_{INT} + P_{IO} = I_{CCINT} \times V_{CC} + P_{IO}$$

The P_{IO} value, which depends on the device output load characteristics and switching frequency, can be calculated using the guidelines given in *Application Note 74 (Evaluating Power for Altera Devices)*. The I_{CCINT} value depends on the switching frequency and the application logic.

The I_{CCINT} value is calculated with the following equation:

$$I_{CCINT} = (A \times MC_{TON}) + [B \times (MC_{DEV} - MC_{TON})] + (C \times MC_{USED} \times \mathbf{f_{MAX}} \times \mathbf{tog_{LC}})$$

Notes:
(1) All pins not listed are user I/O pins.
(2) Perform a complete thermal analysis before committing a design to this device package. See *Application Note 74 (Evaluating Power for Altera Devices)*.
(3) EPM9320A devices are not offered in this package.
(4) During in-system programming, each device's VPP pin must be connected to the 5.0-V power supply. During normal device operation, the VPP pin is pulled up internally and can be connected to the 5.0-V supply or left unconnected.
(5) The user I/O pin count includes dedicated input pins and all I/O pins.

Table 27. EPM9400 Dedicated Pin-Outs *Note (1)*

Pin Name	84-Pin PLCC *(2)*	208-Pin RQFP	240-Pin RQFP
DIN1 (GCLK1)	2	182	210
DIN2 (GCLK2)	1	183	211
DIN3 (GCLR)	12	153	187
DIN4 (GOE)	74	4	234
TCK	43	78	91
TMS	54	49	68
TDI	42	79	92
TDO	31	108	114
GND	6, 13, 20, 26, 27, 47, 60, 66, 69, 73	14, 20, 24, 31, 35, 41, 42, 43, 44, 46, 47, 66, 85, 102, 110, 113, 114, 115, 116, 118, 121, 122, 132, 133, 143, 152, 170, 189, 206	5, 14, 25, 34, 45, 54, 65, 66, 81, 96, 110, 115, 126, 127, 146, 147, 166, 167, 186, 200, 216, 229
VCCINT (5.0 V only)	16, 23, 30, 56, 63, 70	10, 19, 30, 45, 112, 128, 139, 148	4, 24, 44, 64, 117, 137, 157, 177
VCCIO (3.3 or 5.0 V)	17, 37, 59, 80	5, 25, 36, 55, 72, 91, 111, 127, 138, 159, 176, 195	15, 35, 55, 73, 86, 101, 116, 136, 156, 176, 192, 205, 220, 235
No Connect (N.C.)	–	6, 7, 8, 9, 11, 12, 13, 109, 144, 145, 146, 147, 149, 150, 151	1, 2, 3, 6, 7, 8, 9, 10, 11, 12, 13, 168, 169, 170, 171, 172, 173, 174, 175, 178, 179, 180, 181, 182, 183, 184, 185, 236, 237, 238, 239, 240
VPP *(3)*	55	48	67
Total User I/O Pins *(4)*	59	139	159

Notes:
(1) All pins not listed are user I/O pins.
(2) Perform a complete thermal analysis before committing a design to this device package. See *Application Note 74 (Evaluating Power for Altera Devices)* for more information.
(3) During in-system programming, each device's VPP pin must be connected to the 5.0-V power supply. During normal device operation, the VPP pin is pulled up internally and can be connected to the 5.0-V supply or left unconnected.
(4) The user I/O pin count includes dedicated input pins and all I/O pins.

Revision History

Information contained in the *MAX 9000 Programmable Logic Device Family Data Sheet* version 6.5 supersedes information published in previous versions.

Version 6.5

Version 6.6 of the *MAX 9000 Programmable Logic Device Family Data Sheet* contains the following change:

- Added Tables 7 through 9.
- Added "Programming Sequence" on page 20 and "Programming Times" on page 20

Version 6.4

Version 6.4 of the *MAX 9000 Programmable Logic Device Family Data Sheet* contains the following change: Updated text on page 23.

Version 6.3

Version 6.3 of the *MAX 9000 Programmable Logic Device Family Data Sheet* contains the following change: added Note (7) to Table 16.

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